What is claimed is:

1. 1. A method of testing a receiver comprising:

2   driving a signal into a reference load;

3   modifying the signal to achieve a characteristic eye pattern;

4   replacing the reference load with the receiver; and

5   verifying the receiver output.

1. 2. The method of claim 1 wherein the characteristic eye pattern comprises an

2   eye voltage.

1. 3. The method of claim 1 wherein the characteristic eye pattern comprises an

2   eye time.

1. 4. The method of claim 1 wherein driving the signal into a reference load

2   comprises modeling a driver and reference channel.

1. 5. A method of testing a driver comprising:

2   driving a reference channel; and

3   measuring at least one parameter at an output of the reference channel.

1. 6. The method of claim 5 wherein the method is performed by computer

2   simulation.

1. 7. The method of claim 6 wherein the reference channel is specified by s-

2   parameters.

1. 8. The method of claim 6 wherein the reference channel is specified at least in

2   part by a loss versus frequency characteristic.

1   9.   The method of claim 8 wherein the reference channel is further specified by
2   a minimum delay.

1   10.   The method of claim 8 wherein the reference channel is further specified by
2   a maximum delay.

1   11.   The method of claim 5 wherein the at least one parameter includes an eye
2   voltage.

1   12.   The method of claim 5 wherein the at least one parameter includes an eye
2   time.

1   13.   The method of claim 5 wherein the reference channel is specified at least in
2   part by a delay versus frequency characteristic.

1   14.   A method comprising:
2   coupling a device under test to a reference channel; and
3   measuring at least one parameter at an output of the reference channel.

1   15.   The method of claim 14 wherein the device under test comprises a receiver.

1   16.   The method of claim 14 wherein the device under test comprises a driver.

1   17.   The method of claim 14 wherein the at least one parameter comprises an eye
2   voltage.

1   18.   The method of claim 14 wherein the at least one parameter comprises an eye
2   time.

1 19.   The method of claim 14 wherein the method is performed by computer
2 simulation.

1 20.   The method of claim 19 wherein the reference channel is defined by a set of
2 reference channel parameters.

1 21.   The method of claim 20 wherein the set of reference channel parameters
2 comprises s-parameters.

1 22.   The method of claim 20 wherein the set of reference channel parameters
2 comprises a loss value.

1 23.   The method of claim 22 wherein the set of reference channel parameters
2 further comprises a delay value.

1 24.   An apparatus including a medium adapted to hold machine-accessible
2 instructions that when accessed result in a machine performing:
3   coupling a device under test to a reference channel; and
4   measuring at least one parameter at an output of the reference channel.

1 25.   The apparatus of claim 24 wherein the device under test comprises a
2 receiver.

1 26.   The apparatus of claim 24 wherein the device under test comprises a driver.

1 27.   The apparatus of claim 24 wherein the at least one parameter comprises an
2 eye time.

1 28.   An electronic system comprising:
2   a processor capable of simulating a circuit; and

3   an SRAM storage medium accessible by the processor, the storage medium

4   to hold instructions that when accessed result in the processor performing:

5   coupling a device under test to a reference channel; and

6   measuring at least one parameter at an output of the reference channel.

1   29.   The electronic system of claim 28 wherein the device under test comprises a

2   receiver.

1   30.   The electronic system of claim 28 wherein the device under test comprises a

2   driver.